TTTC IN GENERAL

PURPOSE: The Test Technology Technical Council is a volunteer professional organization sponsored by the IEEE Computer Society. The goals of TTTC are to contribute to members’ professional development and advancement and to help them solve engineering problems in electronic test, and help advance the state-of-the-art. In particular, TTTC aims at facilitating the knowledge flow in an integrated manner, to ensure overall quality in terms of technical excellence, fairness, openness, and equal opportunities.

MEMBERSHIP: Membership is open to all individuals interested in test engineering at a professional level.

DUES: There are NO dues for TTTC membership and no parent-organization membership requirements.

BENEFITS: The TTTC members benefit from personal association with other test professionals. They may have the opportunity to be involved on a wide range of committees. They receive appropriate and updated information and announcements. There are substantial reductions in fees for TTTC-sponsored meetings and tutorials for members of IEEE and/or IEEE Computer Society.

TTTC ACTIVITIES

TECHNICAL MEETINGS: To spread technical knowledge and advance the state-of-the-art, TTTC sponsors many well-known conferences and symposia and holds numerous regional and topical workshops worldwide.

STANDARDS: TTTC initiates, nurtures and encourages new test standards. TTTC-initiated Working Groups have produced numerous IEEE standards, including the 1149 series used throughout the industry.

TECHNICAL ACTIVITIES: TTTC sponsors a number of Technical Activity Committees (TACs) that address emerging test technology topics and guide a wide range of activities.

TUTORIALS and EDUCATION: TTTC sponsors a comprehensive Test Technology Educational Program (TTEP). This program provides opportunities for design and test professionals to update and expand their knowledge base in test technology, and to earn official accreditation from IEEE TTTC, upon the completion of four full day tutorials proposed by TTEP.

TTTC CONTACT

TTTC On-Line: The TTTC Web Site at http://tab.computer.org/tttc offers samples of the TTTC Newsletter, information about technical activities, conferences, workshops and standards, and links to the Web pages of a number of TTTC-sponsored technical meetings.

Becoming a MEMBER: Becoming a TTTC member is extremely simple. You may either contact by phone or e-mail the TTTC office, or fill out and submit a TTTC application form, or visit the membership section of the TTTC web site.

TTTC OFFICE: 1474 Freeman Drive, Amissville, VA 20106, USA
Phone: +1-540-937-8280  Fax: +1-540-937-7848  E-mail:tttc@computer.org
TTTC Officers for 2008

Chair  Adit D. SINGH  Auburn Univ. - USA  adsingh@eng.auburn.edu
1st Vice Chair  Michael NICOLAI DIs  TIMA Laboratory - France  michael.nicolaidis@imag.fr
2nd Vice Chair  Chen-Hu an CHIANG  Acalat-Lucent - USA  chenhu an@alcatel-lucent.com
President of Board  Yervant ZORIAN  Virage Logic Corp. - USA  zorian@viragelogic.com
Past Chair  André IVANOV  U. of British Columbia - Canada  ivanov@ece.ubc.ca
Senior Past Chair  Paolo PRINETTO  Politecnico di Torino - Italy  paolo.prinetto@polito.it
IEEE Design & Test EIC  K.T. (Tim) CHENG  UC Santa Barbara - USA  timcheng@ece.ucsb.edu
ITC General Chair  Doug J. YOUNG  SV Probe Inc. - USA  dyou ng@svprobe.com
Test Week Coordinator  Yervant ZORIAN  Virage Logic Corp. - USA  zorian@viragelogic.com
Secretary  Christian LANDRAUL T  LIRM M - France  landrault@irmm.fr
Vice Secretary  Adam OSSEIR AN  Edith Cowan U. - Australia  a.osseiran@ecu.edu.au
Finance Chair  Michael NICOLAI DIs  TIMA Laboratory - France  michael.nicolaidis@imag.fr
Finance Vice-Chair  Don WHEATER  IBM Microelectronics - USA  dwh eater@us.ibm.com

Group Chairs

Technical Meetings  Chen-Hu an CHIANG  Acalat-Lucent- USA  chenhu an@alcatel-lucent.com
Technical Activities  Matteo SONZA REORDA  Politecnico di Torino – Italy  matteo.sonzareord a@polito.it
Tutorials & Education  Dimitris GIZOPOULOS  University of Piraeus - Greece  dgizopoulos@uniipi.gr
Standards  Rohit KAPUR  Synopsys, Inc. - USA  rkapur@synopsys.com
Communications  Cecilia METRA  U. of Bologna - Italy  cm met ra@deis.unibo.it
Standing Committees  André IVANOV  U. of British Columbia - Canada  ivanov@ece.ubc.ca
Industry Advisory Board  Yervant ZORIAN  Virage Logic Corp. - USA  zorian@viragelogic.com
Electronic Media  Alfredo BENSO  Politecnico di Torino - Italy  alfred o.benso@polito.it
Asia & Pacific  Kazumi HATAYAMA  STARC - Japan  hatayama.kazumi@starc.or.jp
Europe  Zebo PENG  Linköping U. - Sweden  zpe@ida.liu.se
Latin America  Victor Hugo CHAMPAC  Inst. Nat. de Astrofisica - Mexico  champac@inaoep.mx
North America  William MANN  Southwest Test Workshop - USA  william.mann@ieee.org
Middle East & Africa  Ibrahim HAJJ  American U. of Beirut - Lebanon  ialj@aub.edu.lb

Technical Activity Committees

Board Testing  Bill EKLOW  Cisco Systems - USA  ben@df t.co.uk
Defect Tolerance  Vincenzo PIURI  Politecnico di Milano - Italy  piuri@elet.polimi.it
Economics of Test  Magdy S. ABA DIR  Freescale, Inc. - USA  m.abadir@freescale.com
Embedded Core Test  Anthony P. AMBLER  U. of Texas at Austin - USA  ambler@ece.utexas.edu
FPGA Testing  Yervant ZORIAN  Virage Logic Corp. - USA  zorian@viragelogic.com
Freeware libraries  Michel RENOVEL L  LIRM M - France  renovell@irmm.fr
IEEE 1149.1  Christopher J. CLARK  Intellec tech Corporation - USA  cjclark@intellectech.com
Infrastructure IP  Yervant ZORIAN  Virage Logic Corp. - USA  zorian@viragelogic.com
Memory Testing  R ochi t RAJSU MAN  Advantest - USA  r.rajsuman@advantest.com
MEMs Testing  Ronald D. BLANTON  Carnegie-Mellon U. - USA  blanton@ece.cmu.edu
Mixed-Signal Testing  Bernard COURTOIS  TIM A - France  bernard.courtois@imag.fr
Nano Technology  Bozena KAMINSKA  IMS Pultronics, Inc. - USA  bozena@pultronics.com
Network-Off-Chip Test  Jaume SEGURA  U. of the Balearic Islands - Spain  dfsegura@iulist.unib s.es
On-Line Testing  Fabrizio LOMBARDI  Northeastern U. - USA  lombardi@ece.neu.edu
RF Testing  Erik Jan MARINISSEN  NXP – The Netherlands  erik.jan.marinissen@nxp.com
Silicon Debug and Diagnosis  Michael NICOLAI DIs  iROC Technologies - France  michael.nicolaidis@roc tech.com
SIP Testing  Bernard COURTOIS  TIM A - France  bernard.courtois@imag.fr
System Test  Ian HARRIS  UC Irvine - USA  harris@ics.ucl.edu
Test Compression  Mick TEGETHOFF  Cadence - USA  mickt@cadence.com
Test & Verification  Magdy S. ABA DIR  Freescale, Inc. - USA  m.abadir@freescale.com
Test Education  Sule OZEV  Duk e U. - USA  sule@ee.duke.edu
Test Synthesis  Scott DAVIDSON  Sun Microsystems - USA  scott.david son@eng.sun.com
Thermal Testing  Bernard COURTOIS  TIM A - France  bernard.courtois@imag.fr

Standards Working Groups

IEEE 1149.4  Bambang SUPARJO  Mentor Graphics - USA  bambang_supar jo@mentor.com
IEEE 1149.6  Bill EKLOW  Cisco Systems, Inc. - USA  beklow@cisco.com
IEEE P1149.7  Robert OSHANA  Texas Instruments - USA  roshana@ti.com
IEEE 1450-1999  Gregory MASTON  Synopsys, Inc. - USA  gmaston@synopsys.com
IEEE 1450.1  Tony TAYLOR  t.taylor@ieee.org
IEEE 1450.2-2002  Gregg WILDER  Texas Instruments - USA  gwilder@ti.com
IEEE P1450.3  Tony TAYLOR  t.taylor@ieee.org
IEEE P1450.4  Doug SPRAGUE  IBM - USA  dsprague@us.ibm.com
IEEE P1450.5  Jim O’REILLY  Analog Devices - USA  jim_oreilly@ieee.org
TTTC-Sponsored Technical Meetings in 2008
For the most current information, please visit the TTTC website (http://tab.computer.org/tttc) or TTTC Events website (http://www.tttc-events.org)

1/23-1/25 Int'l Symposium on Electronic, Design, Test and Applications (DELA), Hong Kong, PRC A. Bermak
2/17-2/20 Latin American Test Workshop (LATW), Puebla, Mexico V. Champac
3/10-3/14 Design, Automation and Test in Europe (DATE), Munich, Germany D. Scolto
3/26-3/27 Workshop on Silicon Errors in Logic - System Effects (SELSE), Austin, TX, USA W. Bartlett
4/7-4/9 International Test Synthesis Workshop (ITSW), Santa Barbara, CA, USA N. Mukherjee
4/16-4/18 Design & Diagnosis of Electronic Circuits & Systems Workshop (DDECIS), Bratislava, Slovakia M. Renovell
4/27 Workshop on Test of Wireless Circuits and Systems (WTW), San Diego, CA, USA R. Aitken
4/27-5/1 VLSI Test Symposium (VTS), San Diego, CA, USA A. Oraloglu
4/30-5/1 International Silicon Debug and Diagnosis Workshop (SDD), San Diego, CA, USA F. Muradali
5/12-5/15 Workshop on Signal Propagation on Interconnects (SPI), Avignon, France D. Deschacht
5/22-5/25 Int'l Conference on Automation, Quality & Testing, Robotics (AQTR), Cluj-Napoca, Romania L. Miclea
5/25-5/29 European Test Symposium (ETS), Lago Maggiore, Italy M. Sonza Reorda
6/18-6/20 Int'l Mixed-Signals, Sensors, and Systems Test Workshop (IMS3TW), Vancouver, Canada A. Ivanov
7/7-7/9 International On-Line Testing Symposium (IOLTS), Rhodes, Greece M. Nikolaidis
9/5-9/9 East-West Design and Test Symposium (EWDTS), Lvov, Ukraine V. Hahanov
9/16-9/18 Board Test Workshop (BTW), Fort Collins, CO, USA W. Eklow
9/29-9/30 Int'l Workshop on Design & Test of Nano Devices, Circuits and Systems (NDCS), MA, USA G. Baccarani, F. Lombardi
10/1-10/3 Int'l Symposium on Defect & Fault Tolerance in VLSI Systems (DFT), Cambridge, MA, USA C. Bolchini
10/10-10/30 International Test Conference (ITC), Santa Clara, CA, USA D. Young
10/30-10/31 ATE: Vision 2020, Santa Clara, CA, USA E. Volkerink
10/30-10/31 Design for Reliability, Santa Clara, CA, USA M. Nikolaidis
11/12-11/13 Int'l Workshop on Design for Manufacturability & Yield (DFM&Y), San Jose, CA, USA Y. Zorian
11/16-11/18 Int'l High Level Design Validation and Test Workshop (HLDVT), Lake Tahoe, NV, USA P. Varma
11/24-11/27 Asian Test Symposium (ATS), Sapporo, Japan Y. Sato
11/27-11/28 Workshop on RTL and High Level Testing (WRTL), Sapporo, Japan T. Inoue
11/TBD International Workshop on Microprocessor Test and Verification (MTV), Austin, TX, USA M. Abadir
12/4-12/5 Int'l Workshop on Testing Embedded and Core-Based System-Chips (TECS), Online Y. Zorian
12/20-12/22 International Design & Test Workshop (IDT), TBD H. El Tahawy

TTTC Office

1474 Freeman Drive
Amissville, VA 20106
USA

Phone: +1-540-937-8280
Fax: +1-540-937-7848
E-mail: tttc@computer.org

http://tab.computer.org/tttc